TOSHIBA Photocoupler Photorelay

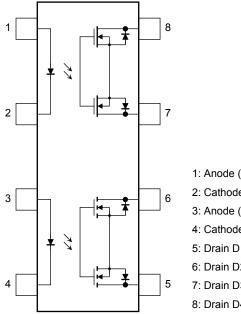
# **TLP4007G**

**Telecommunication Measurement Equipment** Security Equipment FA

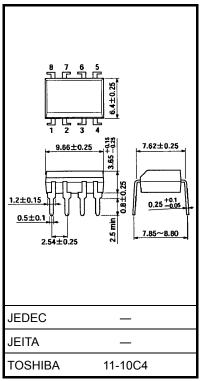
The Toshiba TLP4007G consists of an aluminum gallium arsenide infrared emitting diode optically coupled to a photo-MOSFET and is the 1-form-A/B photorelay with 350-V withstanding voltage.

- Normally closed (1-form-B) device, normally opened (1-form-A) device ٠
- Peak off-state voltage: 350 V (min) •
- Trigger LED current: 3 mA (max)
- On-state current: 100 mA (max) •
- On-state resistance: 50  $\Omega$  (max)
- Isolation voltage: 2500 Vrms (min)

# **Pin Configuration (top view)**







Weight: 0.54 g (typ.)

Unit: mm

Absolute Maximum Ratings (Ta = 25°C)

	Charac	Symbol	Rating	Unit	
	Forward current		١ <sub>F</sub>	50	mA
LED	Forward current derating (Ta	∆I <sub>F</sub> /°C	-0.5	mA/°C	
	Peak forward current		I <sub>FP</sub>	1	А
	Reverse voltage	V <sub>R</sub>	5	V	
	Junction temperature		Tj	125	°C
	Off-state output terminal volt	V <sub>OFF</sub>	350	V	
		One channel operation			
Detector	On-state current	Two channel operations (1a1b simultaneous operation)	I <sub>ON</sub>	100	mA
Dete		One channel operation			
	On-state current derating (Ta ≧ 25°C)	Two channel operations (1a1b simultaneous operation)	∆l <sub>ON</sub> /°C	-1.0	mA/°C
	Junction temperature		Tj	125	°C
Stora	age temperature range	T <sub>stg</sub>	-55 to 125	°C	
Oper	rating temperature range	T <sub>opr</sub>	-40 to 85	°C	
Lead	soldering temperature (10 s)	T <sub>sol</sub>	260	°C	
Isola	tion voltage (AC, 1 min, R.H.	BVS	2500	Vrms	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Pins 1, 2, 3 and 4 are shorted together, and pins 5, 6, 7 and 8 are shorted together.

#### **Recommended Operating Conditions**

Characteristics	Symbol	Min	Тур.	Max	Unit
Supply voltage	V <sub>DD</sub>			280	V
Forward current	١ <sub>F</sub>	5	10	25	mA
On-state current	I <sub>ON</sub>	_	_	100	mA
Operating temperature	T <sub>opr</sub>	-20		65	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

## Electrical Characteristics (Ta = 25°C)

	Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
	Forward voltage	VF	I <sub>F</sub> = 10 mA	1.0	1.15	1.3	V
LED	Reverse current	I <sub>R</sub>	$V_R = 5 V$	_	_	10	μA
	Capacitance	CT	V = 0, f = 1 MHz	_	30	_	pF
or	Off-state current	IOFF	V <sub>OFF</sub> = 350 V	_	_	1	μA
Detector	Capacitance (1b)	C	$V = 0, f = 1 \text{ MHz}, I_F = 5 \text{ mA}$		30		۶E
	Capacitance (1a)	C <sub>OFF</sub>	V = 0, f = 1 MHz		30		pF

# **Coupled Electrical Characteristics (Ta = 25°C)**

Characteristics	Form	Symbol	Test Condition	Min	Тур.	Max	Unit
Trigger LED current	1a	I <sub>FT</sub>	I <sub>ON</sub> = 100 mA	1		3	mA
	1b	I <sub>FC</sub>	$I_{OFF} = 10 \ \mu A$			5	III/A
Return LED current	1a	I <sub>FC</sub>	$I_{OFF} = 10 \ \mu A$	0.1	_	_	mA
	1b	I <sub>FT</sub>	I <sub>ON</sub> = 100 mA				IIIA
On-state resistance (Note 2)	—	R <sub>ON</sub>	I <sub>ON</sub> = 100 mA, t < 1s	_	27	35 50	Ω
			I <sub>ON</sub> = 100 mA	_	40		52

Note 2: 1-form-A:  $I_F = 5 \text{ mA}$ , 1-form-B:  $I_F = 0 \text{ mA}$ 

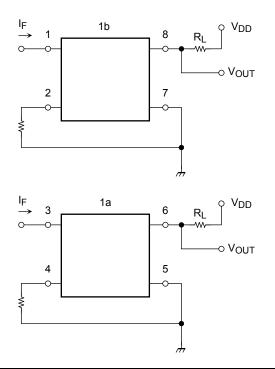
#### Isolation Characteristics (Ta = 25°C)

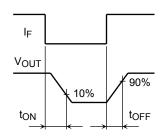
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Capacitance input to output	CS	$V_S = 0, f = 1 MHz$	—	0.8	_	pF
Isolation resistance	R <sub>S</sub>	$V_{S} = 500 \text{ V}, \text{ R.H.} \le 60\%$	$5  imes 10^{10}$	10 <sup>14</sup>	_	Ω
		AC, 1 min	2500	_	_	Vrms
Isolation voltage		AC, 1 s, in oil	—	5000	_	
		DC, 1 min, in oil	—	5000	_	Vdc

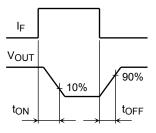
# Switching Characteristics (Ta = 25°C)

	Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
1b	Turn-on time	t <sub>ON</sub>	R <sub>L</sub> = 200 Ω	_	0.25	1	ms
10	Turn-off time	tOFF	$V_{DD} = 20 \text{ V}, \text{ I}_{\text{F}} = 5 \text{ mA} \qquad (\text{Note } 3)$	_	0.5	1	
1a	Turn-on time	t <sub>ON</sub>	RL = 200 Ω	_	0.3	1	ms
Та	Turn-off time	tOFF	$V_{DD} = 20 \text{ V}, \text{ I}_{\text{F}} = 5 \text{ mA}$ (Note 3)	_	0.15	1	1115

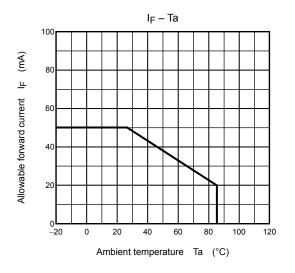
Note 3: Switching time test circuit

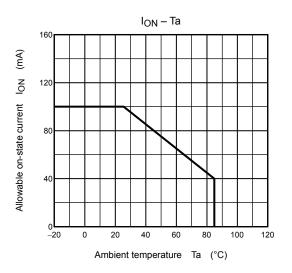


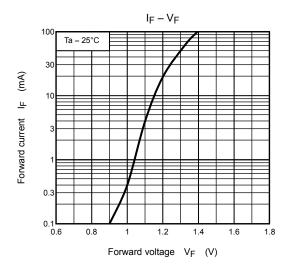




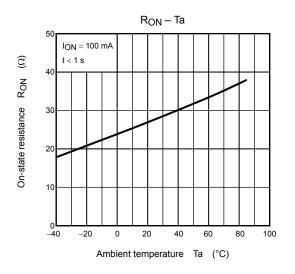
## Characteristics curves for 1-form-A/B

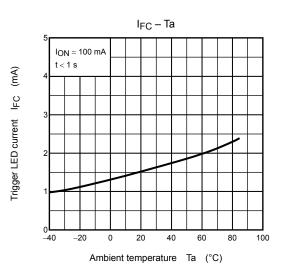


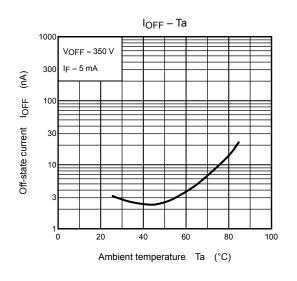


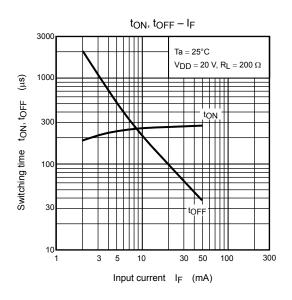


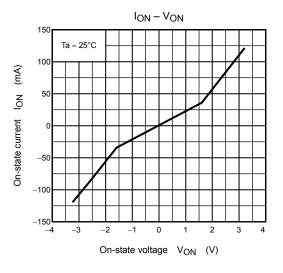
#### Characteristics curves for 1-form-B

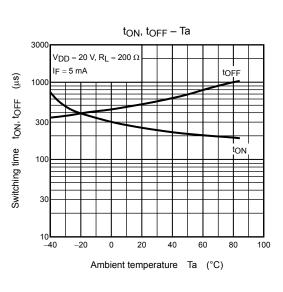




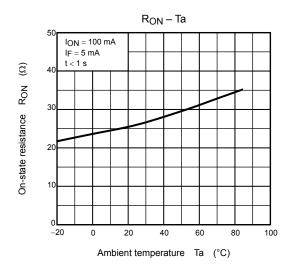


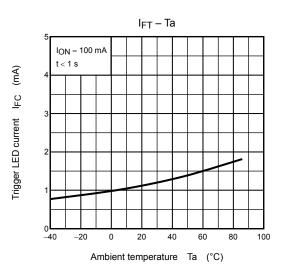


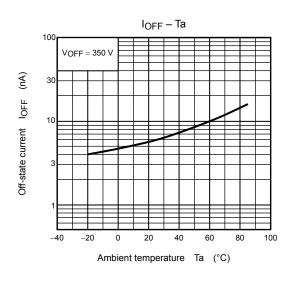


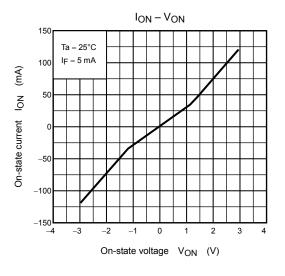


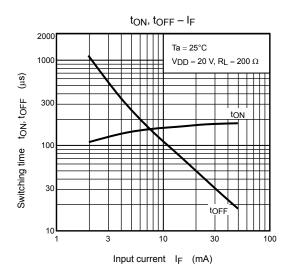
## Characteristics curves for 1-form-A

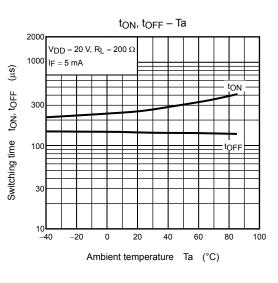












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